

### **High-level fault diagnosis in RISC processors with Implementation-Independent Functional Test**

**Oyeniran, Adeboye Stephen; Jenihhin, Maksim; Raik, Jaan; Ubar, Raimund-Johannes** 2022 IEEE Computer Society Annual Symposium on VLSI (ISVLSI) : Nicosia, Cyprus : 04-06 July 2022 / p. 32-37 <https://doi.org/10.1109/ISVLSI54635.2022.00019>

### **Implementation-independent functional test generation for RISC microprocessors**

**Oyeniran, Adeboye Stephen; Ubar, Raimund-Johannes; Jenihhin, Maksim; Raik, Jaan** VLSI-SoC 2019 : 27th IFIP/IEEE International Conference on Very Large Scale Integration : [proceedings] 2019 / p. 82-87 : ill <https://doi.org/10.1109/VLSI-SoC.2019.8920323>

### **Implementation-independent test generation for a large class of faults in RISC processor modules**

**Jenihhin, Maksim; Oyeniran, Adeboye Stephen; Raik, Jaan; Ubar, Raimund-Johannes** 24th Euromicro Conference on Digital System Design (DSD) 2021 <https://doi.org/10.1109/DSD53832.2021.00090>

### **On test generation for microprocessors for extended class of functional faults**

**Oyeniran, Adeboye Stephen; Ubar, Raimund-Johannes; Jenihhin, Maksim; Raik, Jaan** VLSI-SoC: New technology enabler : 27th IFIP WG 10.5/IEEE International Conference on Very Large Scale Integration, VLSI-SoC 2019 Cusco, Peru, October 6–9, 2019 : Revised and Extended Selected Papers 2020 / p. 21-44 <https://doi.org/10.1007/978-3-030-53273-4> [Conference proceedings at Scopus](#)  
[Article at Scopus](#)